

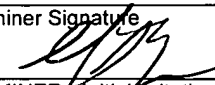
Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 11540-004001	Application No.
	Applicant Henry A. Hill			
	Filing Date July 27, 2001		Group Art Unit	

 1000 U.S. PTO  
09/01/2001

07/27/01

U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
SY	AA	4,659,429	04/1987	Isaacson et al.			
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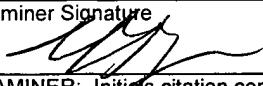
Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
SY	AX	0 409 468 A2	01/1991	Europe				

Examiner Signature 	Date Considered 12/1/02
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
SV	AY	0 757 271 A2	02/1997	Europe				
	AZ	5-174410	05/1993	Japan				✓
	AAA	5-73980	05/1993	Japan				✓

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SV	ABB	Bauer et al., "Magnetic Domain Imaging with a Scanning Near-Field Optical Microscope Using a Modified Sagnac Interferometer," <u>Journal of Microscopy</u> , 194:2/3:507-511, May/June 1999. ✓
SV	ACC	Courjon et al., "New Optical Near Field Developments: Some Perspectives in Interferometry," <u>Ultramicroscopy</u> , 61:117-125, 1995. ✓
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SV	AEE	Pohl et al., "Near-field Optics: Light for the World of NANO," <u>J. Vac. Sci. Technol. B</u> , 12:3:1441-1446, May/June 1994. ✓
SV	AFF	Vaez-Iravani et al., "Phase Contrast and Amplitude Pseudoheterodyne Interference Near Field Scanning Optical Microscopy," <u>Appl. Phys. Lett.</u> 62:10:1044-1046, March 8, 1993. ✓
SV	AGG	Fischer, "Optical Characteristics of 0.1 $\mu$ m Circular Apertures in a Metal Film as Light Sources for Scanning Ultramicroscopy," <u>J. Vac. Sci. Technol. B</u> 3:1:386-390, Jan/Feb 1985. ✓
SV	AHH	Fischer et al., "Near-Field Optical Scanning Microscopy and Enhanced Spectroscopy with Submicron Apertures," <u>Scanning Microscopy Supplement</u> , 1:47-52, 1987. ✓
SV	ALL	Durig et al., "Near-Field Optical-Scanning Microscopy," <u>J. Appl. Phys.</u> 59:10:3318-3327, May 15, 1986. ✓
SV	AJJ	Meixner et. al., "Direct Measurement of Standing Evanescent Waves with a Photon-Scanning Tunneling Microscope," <u>APPLIED OPTICS</u> , 33:34:7995-8000, December 1, 1994. ✓
SV	AKK	Bainier et al., "Evanescent Interferometry by Scanning Optical Tunneling Detection," <u>J. Opt. Soc. Am. A</u> , 13:2:267-275, February 1996. ✓
SV	ALL	Guerra, "Photon Tunneling Microscopy," <u>APPLIED OPTICS</u> , 29:26:3741-3752, September 10, 1990. ✓

Examiner Signature 	Date Considered 12/1/02
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Substitute Form PTO-1449 (Modified) <b>OCT 21 2002</b> <b>Information Disclosure Statement</b> <b>by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 11540-005001	Application No. 09/917,400
	Applicant Henry A. Hill		
	Filing Date July 27, 2001	Group Art Unit 2881	

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
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**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
SK	AL	0 944 049 A2	09/1999	Europe				
SK	AM	WO99/63300	12/1999	PCT International				
	AN							
	AO							
	AP							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

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